



## Product/Process Change Notice - PCN 18\_0171 Rev. C

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

*Note: Revised fields are indicated by a red field name. See Appendix B for revision history.*

**PCN Title:** ADA4522 Die Revision

**Publication Date:** 20-Aug-2020

**Effectivity Date:** 20-Aug-2020 *(the earliest date that a customer could expect to receive changed material)*

**Revision Description:**  
Updating qualification results.

**Description Of Change:**  
Changes to the Metal 1 / Via / Metal 2 layers. All models will be affected.

**Reason For Change:**  
Improved power on start-up robustness for both high source impedance configurations and high supply current conditions.

**Impact of the change (positive or negative) on fit, form, function & reliability:**  
No Impact to fit, form or function. Reliability improved to cover application with power on start-up and high source impedance.

**Product Identification** *(this section will describe how to identify the changed material)*  
Material will be separated by date code for conversion to the new die. ADA4522-2 cutover date was 1918.

**Summary of Supporting Information:**  
Qualification has been performed per Industry Standard Test Methods. See attached Qualification Results Summary.

### Supporting Documents

**Attachment 1:** Type: Qualification Results Summary  
ADI\_PCN\_18\_0171\_Rev\_C\_ADA4522-1\_Qualification\_Results\_Summary.pdf

**Attachment 2:** Type: Qualification Results Summary  
ADI\_PCN\_18\_0171\_Rev\_C\_ADA4522-2\_Qualification\_Results\_Summary.pdf

**Attachment 3:** Type: Qualification Results Summary  
ADI\_PCN\_18\_0171\_Rev\_C\_ADA4522-4\_Qualification\_Results\_Summary.pdf

**For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.**

**Americas:**  
PCN\_Americas@analog.com

**Europe:**  
PCN\_Europe@analog.com

**Japan:**  
PCN\_Japan@analog.com

**Rest of Asia:**  
PCN\_ROA@analog.com

**Appendix A - Affected ADI Models****Existing Parts - Product Family / Model Number (18)**

ADA4522-1 / ADA4522-1ARMZ	ADA4522-1 / ADA4522-1ARMZ-R7	ADA4522-1 / ADA4522-1ARMZ-RL	ADA4522-1 / ADA4522-1ARZ	ADA4522-1 / ADA4522-1ARZ-R7
ADA4522-1 / ADA4522-1ARZ-RL	ADA4522-2 / ADA4522-2ARMZ	ADA4522-2 / ADA4522-2ARMZ-R7	ADA4522-2 / ADA4522-2ARMZ-RL	ADA4522-2 / ADA4522-2ARZ
ADA4522-2 / ADA4522-2ARZ-R7	ADA4522-2 / ADA4522-2ARZ-RL	ADA4522-4 / ADA4522-4ARUZ	ADA4522-4 / ADA4522-4ARUZ-R7	ADA4522-4 / ADA4522-4ARUZ-RL
ADA4522-4 / ADA4522-4ARZ	ADA4522-4 / ADA4522-4ARZ-R7	ADA4522-4 / ADA4522-4ARZ-RL		

**Appendix B - Revision History**

<b>Rev</b>	<b>Publish Date</b>	<b>Effectivity Date</b>	<b>Rev Description</b>
Rev. -	20-Dec-2018	28-Feb-2019	Initial Release.
Rev. A	20-May-2019	22-Aug-2019	Add parts. Add Qualification Results for ADA4522-2. Add Qualification Plan for ADA4522-1.
Rev. B	24-Feb-2020	28-May-2020	Add parts ADA4522-4. Add Qualification Results for ADA4522-1. Add Qualification Plan for ADA4522-4. Add conversion date for ADA4522-2.
Rev. C	20-Aug-2020	20-Aug-2020	Updating qualification results.

Analog Devices, Inc.

DocId:8261 Parent DocId:None Layout Rev:7

**Qualification Results Summary of ADA4522-1 Die Revision**

QUALIFICATION PLAN / STATUS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Solder Heat Resistance (SHR) <sup>1</sup>	JEDEC <i>J-STD-020</i>	1 x 30	Pass
Latch-Up	JEDEC <i>JESD78</i>	3/test	Pass ±200 mA, ±41.25 V
Electrostatic Discharge <i>Human Body Model</i> <sup>2</sup>	ESDA/JEDEC <i>JS-001-2011</i>	3/voltage	Pass ±3500 V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JS-002</i>	3/voltage	Pass ±1250 V

<sup>1</sup> Preconditioned per JEDEC J-STD-020 Level 1

**Qualification Results Summary of ADA4522-2 Die Revision**

QUALIFICATION PLAN / STATUS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Solder Heat Resistance (SHR) <sup>1</sup>	JEDEC <i>J-STD-020</i>	1 x 30	Pass
Latch-Up	JEDEC <i>JESD78</i>	3/test	Pass ±200 mA, ±41.25 V
Electrostatic Discharge <i>Human Body Model</i> <sup>2</sup>	ESDA/JEDEC <i>JS-001-2011</i>	3/voltage	Pass ±4000 V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JS-002</i>	3/voltage	Pass ±1250 V

<sup>1</sup> Preconditioned per JEDEC J-STD-020 Level 1

**Qualification Results Summary of ADA4522-4 Die Revision**

QUALIFICATION PLAN / STATUS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Solder Heat Resistance (SHR) <sup>1</sup>	JEDEC <i>J-STD-020</i>	1 x 30	Pass
Latch-Up	JEDEC <i>JESD78</i>	3/test	Pass ±200 mA, ±41.25 V
Electrostatic Discharge <i>Human Body Model</i> <sup>2</sup>	ESDA/JEDEC <i>JS-001-2011</i>	3/voltage	Pass ±3000 V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JS-002</i>	3/voltage	Pass ±1250 V

<sup>1</sup> Preconditioned per JEDEC J-STD-020 Level 1